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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/705,218	11/12/2003	Keith Frank Best	081468-0306625	4107	
909	7590 03/21/2006		EXAM	EXAMINER	
PILLSBUR'	Y WINTHROP SHAW	CHACKO DAVIS, DABORAH			
P.O. BOX 10	500				
MCLEAN, V	/A 22102		ART UNIT	PAPER NUMBER	
•			1756		

DATE MAILED: 03/21/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

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·	Application No.	Applicant(s)	
	10/705,218	BEST ET AL.	
Office Action Summary	Examiner	Art Unit	
	Daborah Chacko-Davis	1756	
The MAILING DATE of this communication Period for Reply	appears on the cover sheet with	the correspondence address	
A SHORTENED STATUTORY PERIOD FOR REWHICHEVER IS LONGER, FROM THE MAILING - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory per - Failure to reply within the set or extended period for reply will, by state Any reply received by the Office later than three months after the material patent term adjustment. See 37 CFR 1.704(b).	B DATE OF THIS COMMUNIC R 1.136(a). In no event, however, may a re- iod will apply and will expire SIX (6) MONT atute, cause the application to become ABA	ATION. bly be timely filed HS from the mailing date of this communication NDONED (35 U.S.C. § 133).	
Status			
 1) Responsive to communication(s) filed on 12 2a) This action is FINAL. 2b) T 3) Since this application is in condition for allocation of accordance with the practice under the condition of the condit	his action is non-final.' wance except for formal matte	·	S
Disposition of Claims			
4) Claim(s) 1-26 is/are pending in the application 4a) Of the above claim(s) is/are without 5) Claim(s) is/are allowed. 6) Claim(s) 1-26 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and are subject to restriction and application Papers 9) The specification is objected to by the Examm 10) The drawing(s) filed on is/are: a) applicant may not request that any objection to the Replacement drawing sheet(s) including the control of the specific and sheet(s) including the control of the specific area of the specific and sheet(s) including the control of the specific and sheet	drawn from consideration. d/or election requirement. hiner. accepted or b) □ objected to be the drawing(s) be held in abeyance	e. See 37 CFR 1.85(a).	d).
11) The oath or declaration is objected to by the	,,	·	,
Priority under 35 U.S.C. § 119			
12) Acknowledgment is made of a claim for fore a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the papplication from the International Bur * See the attached detailed Office action for a	ents have been received. ents have been received in Appriority documents have been reau (PCT Rule 17.2(a)).	plication No eceived in this National Stage	
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/Paper No(s)/Mail Date 11/03, 04/04.	Paper No(s)	Immary (PTO-413) /Mail Date ormal Patent Application (PTO-152) -	

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 1-5, 8, 10-26, are rejected under 35 U.S.C. 102(b) as being anticipated by U. S. Patent No. 5,436,173 (Houston).

Houston, in the abstract, in col 3, lines 31-67, in col 4, lines 1-67, in col 5, lines 1-54, figures 1a through 1e, discloses forming a semiconductor device includes patterning a substrate (first substrate) on its first surface with alignment markers (trenches, reference 12), forming a protecting layer (insulating layer) over the alignment markers, bonding the substrate with alignment marks (first substrate) with another substrate (sécond substrate) and etching the insulating layer till the protective layer is exposed and forming trenches (references 18a, 18b, 18c) around the alignment markers, forming a patterned layer on the second surface of the first substrate (figure 1e) lithographically, and using the alignment marks to align the first alignment mark with that of the reverse alignment mark (claims 1, 4, 11, 14, 18, 19). Houston, in col 3, lines 45-67, discloses that the insulator layer (protective layer) perform as an etch stop and includes SiO₂ (oxides of dielectric or combination of dielectric material) (claims 2-3, 20). Houston, in col 5, lines 1-22, discloses that the prior to bonding a reflective layer is formed on the protective layer, and devices are formed on the reflective layer, wherein intervening

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layers are selectively removed (utilizing etching and photolithographic techniques) (claims 5, 8, 10, 21-23). Houston, in col 3, lines 45-62, in col 4, lines 60-68, discloses forming the alignment marks and the corresponding reverse alignment marks photolithographically (claims 12, 16, 24). Houston, in col 4, lines 10-55, in col 7, lines 51-67, in col 8, lines 1-27, discloses photolithographically patterning and etching the etch resistant layer on the second surface of the first substrate to form openings (after removing the insulator layer) above the trench (see figure 4d) (claims 13, and 25). Houston, in col 5, lines 43-68, in col 6, lines 1-21, discloses etching the first substrate (using CMP) resulting in a reduction of thickness (claim 15). Houston, in col 6, lines 9-31, discloses forming at least one alignment marker that is positioned relative to the reverse alignment marker (on the second surface of the first substrate) revealed by the trenches (see figure 2h) (claims 17, and 26).

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 6-7, and 9, are rejected under 35 U.S.C. 103(a) as being unpatentable over U. S. Patent No. 5,436,173 (Houston) in view of U. S. Patent No. 6,180,498 (Geffken et al., hereinafter referred to as Geffken).

Houston is discussed in paragraph no. 2.

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Houston, in the abstract, in col 3, lines 31-35, discloses forming a semiconductor device (claims 7, and 9).

The difference between the claims and Houston is that Houston does not disclose that the reflective layer is aluminum (claim 6).

Geffken, in col 2, lines 61-67, in col 3, lines 1-9, discloses that the reflective layer formed on the alignment mark area is an aluminum layer.

Therefore, it would be obvious to a skilled artisan to modify Houston by employing aluminum as the reflective layer as suggested by Geffken because Geffken, in col 5, lines 25-31, discloses that the aluminum reflective layer provides a substantial uniform optical background, and the edges of the aluminum layer provide contrast for alignment of the semiconductor.

Conclusion

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Daborah Chacko-Davis whose telephone number is (571) 272-1380. The examiner can normally be reached on M-F 9:30 - 6:00. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mark F Huff can be reached on (571) 272-1385. The fax phone number for the organization where this application or proceeding is assigned is (571) 273-8300. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For

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more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

dcd

March 14, 2006.

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